


<b>Search Notes</b> 	<b>Application/Control No.</b>		<b>Applicant(s)/Patent under Reexamination</b>	
	10/780,148		KAISE ET AL.	
	<b>Examiner</b>		<b>Art Unit</b>	
	Binh X. Tran		1765	

SEARCHED			
Class	Subclass	Date	Examiner
216	24	3/27/2006	BT
216	26	3/27/2006	BT

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
216	24	3/27/2006	BT
216	26	3/27/2006	BT

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Updated search using	3/27/2006	BT